

# SKiM 270GD128D



SKiM<sup>®</sup> 4

## SPT IGBT Modules

### SKiM 270GD128D

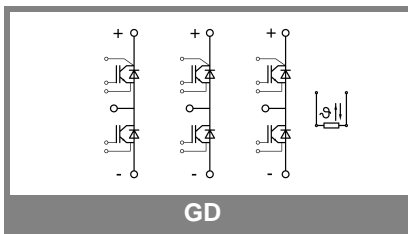
Target Data

#### Features

- N channel, homogenous planar IGBT with n+ buffer layer in SPT (soft punch through) technology
- Isolated by Al<sub>2</sub>O<sub>3</sub> DCB (direct copper bonded) ceramic substrate plate
- Pressure contact technology for thermal contacts
- Spring contact system to attach driver PCB to the auxiliary terminals
- Integrated temperature sensor

#### Typical Applications

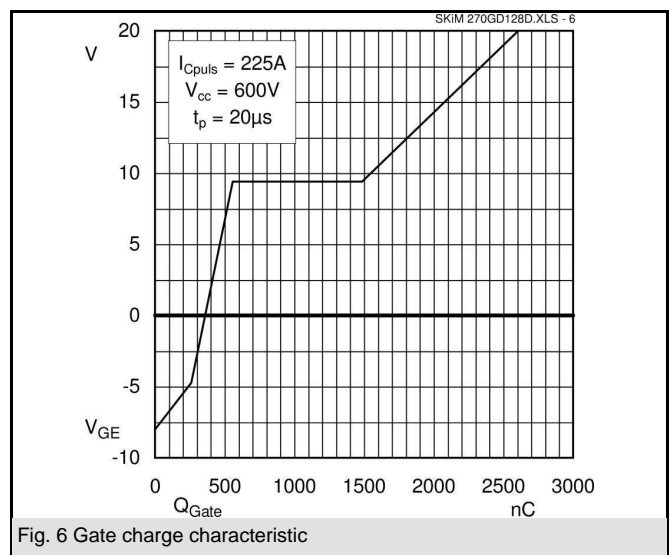
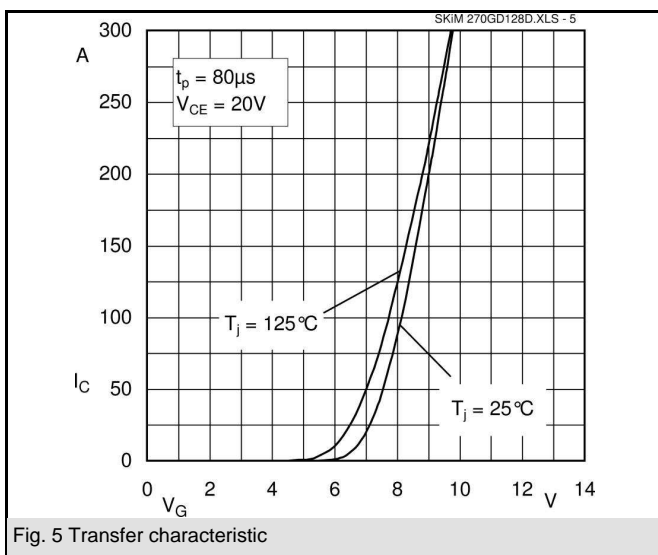
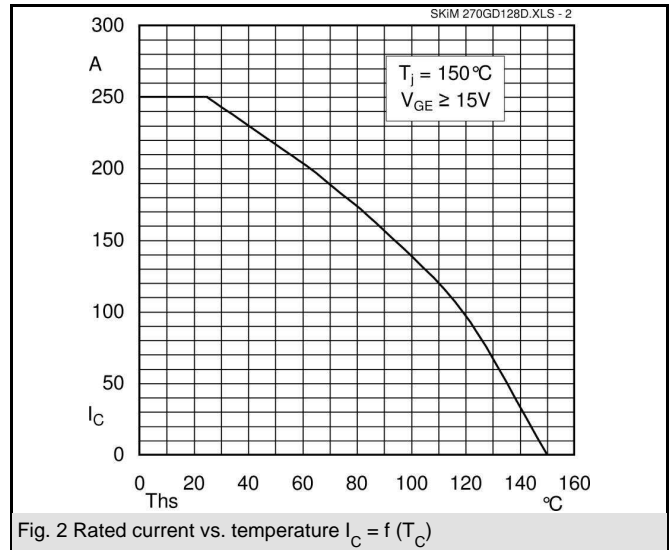
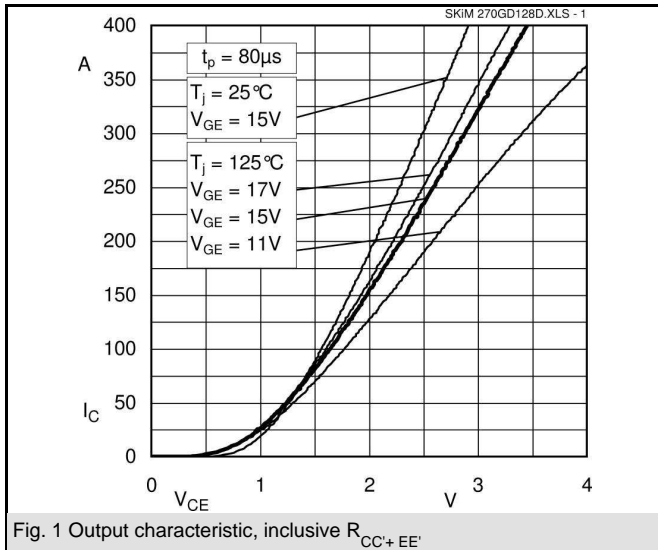
- Switched mode power supplies
- Three phase inverter for AC motor drives

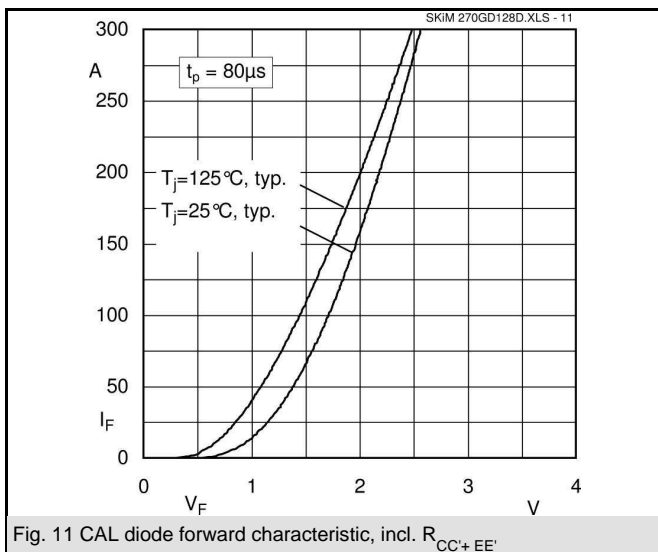
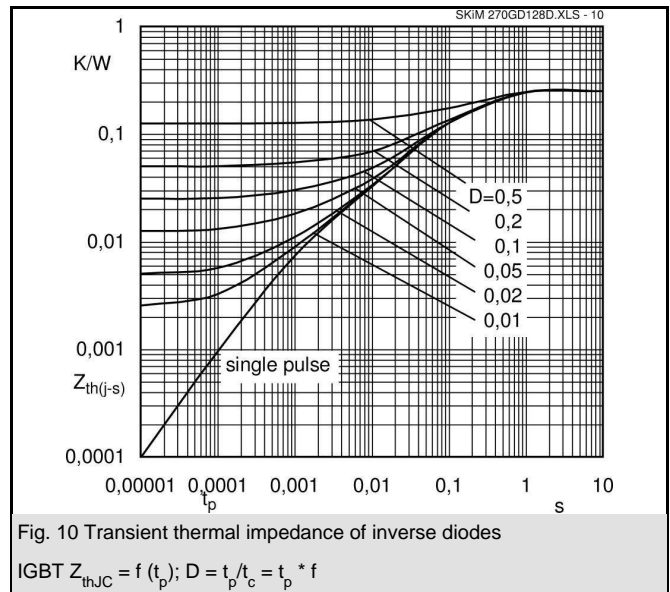
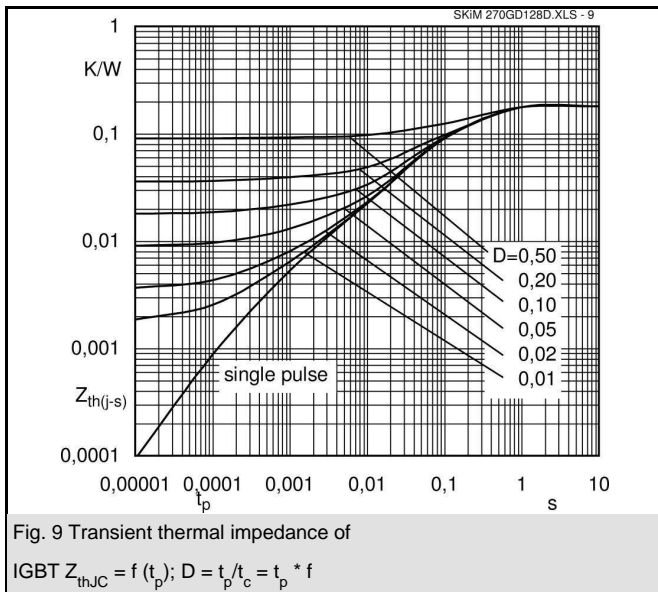


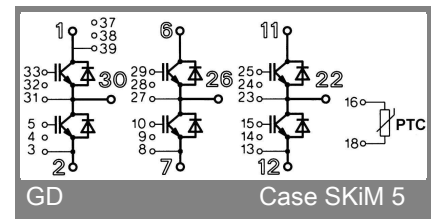
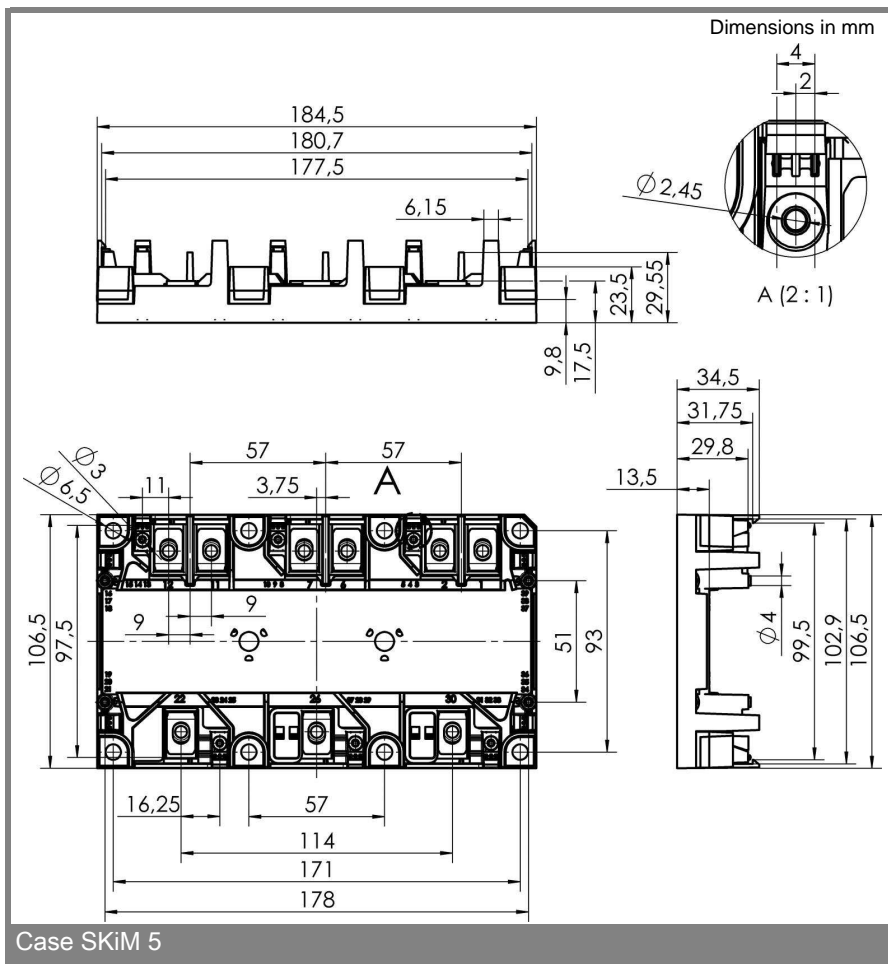
GD

Absolute Maximum Ratings		T <sub>case</sub> = 25°C, unless otherwise specified	
Symbol	Conditions	Values	Units
<b>IGBT</b>			
V <sub>CES</sub>		1200	V
I <sub>C</sub>	T <sub>s</sub> = 25 (70) °C	250 (190)	A
I <sub>CM</sub>	T <sub>s</sub> = 25 (70) °C, t <sub>p</sub> = 1 ms	500 (380)	A
V <sub>GES</sub>		± 20	V
T <sub>j</sub> (T <sub>stg</sub> )		-40 ... +150 (125)	°C
T <sub>cop</sub>	max. case operating temperature	125	°C
V <sub>isol</sub>	AC, 1 min.	2500	V
<b>Inverse diode</b>			
I <sub>F</sub>	T <sub>s</sub> = 25 (70) °C	220 (150)	A
I <sub>FM</sub> = - I <sub>CM</sub>	T <sub>s</sub> = 25 (70) °C, t <sub>p</sub> = 1 ms	500 (380)	A
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.; T <sub>j</sub> = 150 °C		A

Characteristics		T <sub>case</sub> = 25°C, unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
<b>IGBT</b>					
V <sub>GE(th)</sub>	V <sub>GE</sub> = V <sub>CE</sub> ; I <sub>C</sub> = 12 mA	4,45	5,5	6,55	V
I <sub>CES</sub>	V <sub>GE</sub> = 15; V <sub>CE</sub> = V <sub>CES</sub> ; T <sub>j</sub> = 25 °C		0,2	0,6	mA
V <sub>CEO</sub>	T <sub>j</sub> = 25 °C		1 (0,9)	1,15 (1,05)	V
r <sub>CE</sub>	T <sub>j</sub> = 25 ( ) °C		4 (5,3)	5,3 (6,7)	mΩ
V <sub>CESat</sub>	I <sub>C</sub> = 225 A; V <sub>GE</sub> = 15 V, T <sub>j</sub> = 25 (125) °C on chip level		1,9 (2,1)	2,35 (2,55)	V
C <sub>ies</sub>	V <sub>GE</sub> = 0; V <sub>CE</sub> = 25 V; f = 1 MHz		18,6		nF
C <sub>oes</sub>	V <sub>GE</sub> = 0; V <sub>CE</sub> = 25 V; f = 1 MHz		2,2		nF
C <sub>res</sub>	V <sub>GE</sub> = 0; V <sub>CE</sub> = 25 V; f = 1 MHz		2,1		nF
L <sub>CE</sub>				20	nH
R <sub>CC'+EE'</sub>	resistance, terminal-chip T <sub>c</sub> = 25 (125) °C		0,9 (1,1)		mΩ
t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V		160		ns
t <sub>r</sub>	I <sub>C</sub> = 225 A		60		ns
t <sub>d(off)</sub>	R <sub>Gon</sub> = R <sub>Goff</sub> = 4,4 Ω		660		ns
t <sub>f</sub>	T <sub>j</sub> = 125 °C		80		ns
E <sub>on</sub> (E <sub>off</sub> )	V <sub>GE</sub> ± 15 V		20,9 (24,1)		mJ
E <sub>on</sub> (E <sub>off</sub> )	with SKH1 65; T <sub>j</sub> = 125 °C				mJ
	V <sub>CC</sub> = 600 V; I <sub>C</sub> = 225 A				
<b>Inverse diode</b>					
V <sub>F</sub> = V <sub>EC</sub>	I <sub>F</sub> = 225 A; V <sub>GE</sub> = 0 V; T <sub>j</sub> = 25 (125) °C				V
V <sub>TO</sub>	T <sub>j</sub> = 25 (125) °C				V
r <sub>T</sub>	T <sub>j</sub> = 25 (125) °C				mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 225 A; T <sub>j</sub> = 125 °C				A
Q <sub>rr</sub>	V <sub>GE</sub> = 0 V di/dt = A/μs				μC
E <sub>rr</sub>	R <sub>Gon</sub> = R <sub>Goff</sub> = 4,4 Ω		14,5		mJ
<b>Thermal characteristics</b>					
R <sub>th(j-s)</sub>	per IGBT			0,18	K/W
R <sub>th(j-s)</sub>	per FWD			0,25	K/W
<b>Temperature Sensor</b>					
R <sub>TS</sub>	T = 25 (100) °C		1 (1,67)		kΩ
tolerance	T = 25 (100) °C		3 (2)		%
<b>Mechanical data</b>					
M <sub>1</sub>	to heatsink (M5)				Nm
M <sub>2</sub>	for terminals (M6)	4		5	Nm
w				460	g







This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.